Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/083,784	GOODMAN, BRIAN GERARD	
Examiner	Art Unit	
J. Derek Rutten	2192	

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SEARCHED					
Class	Subclass	Date	Examiner		
717	170	3/29/2006	JDR		
711	103	3/29/2006	JDR		
713	100	3/29/2006	JDR		
718	108	3/29/2006	JDR		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
717	170	3/7/2006	JDR	
711	103	3/29/2006	JDR	
713	100	3/29/2006	JDR	
718	/108	3/29/2006	JDR	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	3/8/2006	JDR			
Chameli Das (consulted re. allowabile subject matter)	3/8/2006	JDR			
STIC Database search (Tracking number 169068) - see search history printout	3/14/2006	JDR			
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	3/29/2006	JDR			
717/170,124; 711/103; 713/100; 718/108 - text search - see search history printout	3/29/2006	JDR			
Google - www.google.com ACM - portal.acm.org IEEE - ieeexplore.ieee.org see search history printout	3/29/2006	JDR			